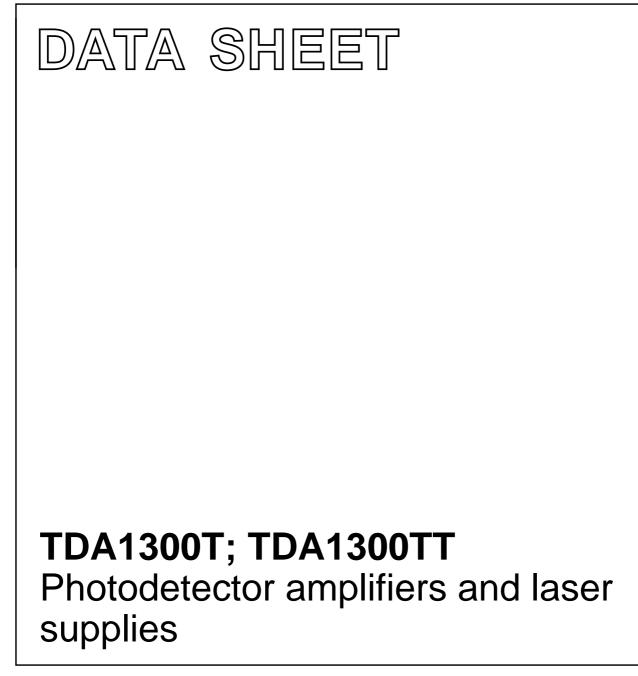
INTEGRATED CIRCUITS



Preliminary specification Supersedes data of 1995 Nov 16 File under Integrated Circuits, IC01 1997 Jul 15



### **TDA1300T; TDA1300TT**

#### FEATURES

- Six input buffer amplifiers with low-pass filtering with virtually no offset
- · HF data amplifier with a high or low gain mode
- Two built-in equalizers for single or double speed mode ensuring high playability in both modes
- Full automatic laser control including stabilization and an on/off switch and containing a separate supply V<sub>DDL</sub> for power reduction
- Applicable with N-sub laser with N-sub or P-sub monitor diode
- Adjustable laser bandwidth and laser switch-on current slope
- Protection circuit preventing laser damage due to supply voltage dip
- Optimized interconnect between pick-up detector and TDA1301
- Wide supply voltage range
- Wide temperature range
- Low power consumption.

#### QUICK REFERENCE DATA

#### **GENERAL DESCRIPTION**

The TDA1300 is an integrated data amplifier and laser supply for three beam pick-up detectors applied in a wide range of mechanisms for Compact Disc (CD) and read only optical systems. It offers 6 amplifiers which amplify and filter the focus and radial diode signals adequately and provides an equalized RF signal for single or double speed mode which can be switched by means of the speed control pin.

The device can handle astigmatic, single Foucault and double Foucault detectors and is applicable with all N-sub lasers and N-sub or P-sub monitor diode units.

After a single initial adjustment the circuit keeps control over the laser diode current resulting in a constant light output power independent of ageing. The chip is mounted in a small SO24 or TSSOP24 package enabling mounting close to the laser pick-up unit on the sledge.

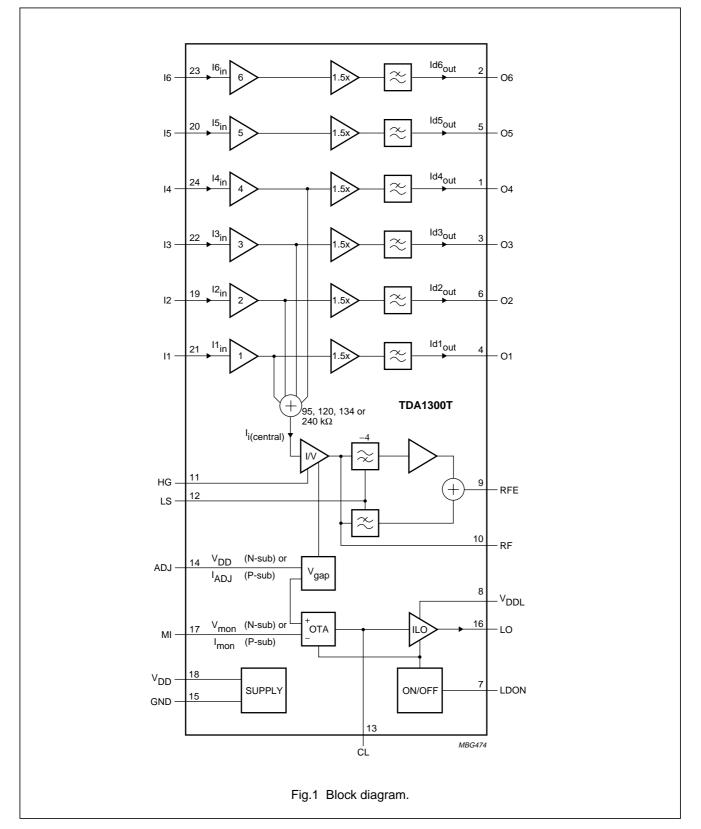
SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT		
V <sub>DD</sub>	supply voltage		3	_	5.5	V		
Diode current amplifiers (n = 1 to 6)								
G <sub>d(n)</sub>	diode current gain		1.43	1.55	1.67			
I <sub>O(d)</sub>	diode offset current		_	_	100	nA		
В	3 dB bandwidth	I <sub>i(d)</sub> = 1.67 μA	50	-	-	kHz		
RFE amplifier	<sup>,</sup> (built-in equalizer)							
t <sub>d(eq)</sub>	equalization delay	f <sub>i</sub> = 0.3 MHz	_	320	-	ns		
t <sub>d(f)</sub>	flatness delay	double speed	_	5	-	ns		
Laser supply	Laser supply							
I <sub>o(L)</sub>	output current	V <sub>DDL</sub> = 3 V	_	_	-100	mA		

#### **ORDERING INFORMATION**

TYPE	PACKAGE				
NUMBER	NAME	E DESCRIPTION			
TDA1300T	SO24	plastic small outline package; 24 leads; body width 7.5 mm	SOT137-1		
TDA1300TT	TSSOP24	plastic thin shrink small outline package; 24 leads; body width 4.4 mm	SOT355-1		

## TDA1300T; TDA1300TT

#### **BLOCK DIAGRAM**

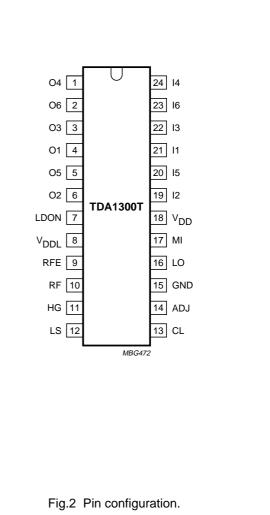


#### Preliminary specification

# Photodetector amplifiers and laser supplies

#### PINNING

SYMBOL	PIN	DESCRIPTION
<b>)</b> 4	1	current amplifier 4 output
O6	2	current amplifier 6 output
03	3	current amplifier 3 output
O1	4	current amplifier 1 output
O5	5	current amplifier 5 output
02	6	current amplifier 2 output
LDON	7	control pin for switching the laser on and off
V <sub>DDL</sub>	8	laser supply voltage
RFE	9	equalized output voltage of sum signal of amplifiers 1 to 4
RF	10	unequalized output
HG	11	control pin for gain switch
LS	12	control pin for speed switch
CL	13	external capacitor
ADJ	14	P-sub monitor (if connected via resistor to GND); N-sub monitor (if connected to V <sub>DD</sub> )
GND	15	ground (substrate connection)
LO	16	laser output; current output
MI	17	monitor diode input (laser)
V <sub>DD</sub>	18	supply
12	19	photo detector input 2 (central)
15	20	photo detector input 5 (satellite)
11	21	photo detector input 1 (central)
13	22	photo detector input 3 (central)
16	23	photo detector input 6 (satellite)
14	24	photo detector input 4 (central)



TDA1300T; TDA1300TT

## Photodetector amplifiers and laser supplies

#### FUNCTIONAL DESCRIPTION

The TDA1300T; TDA1300TT can be divided into two main sections:

- · Laser control circuit section
- Photo diode signal filter and amplification section.

#### Laser control circuit section

The main function of the laser control circuit is to control the laser diode current in order to achieve a constant light output power. This is done by monitoring the monitor diode. There is a fixed relation between light output power of the laser and the current of the monitor diode. The circuit can handle P-sub or N-sub monitor diodes.

#### N-sub MONITOR

In this event pin 14 (ADJ) must be connected to the positive supply voltage  $V_{DD}$  to select the N-sub mode. With an adjustable resistor ( $R_{ADJn}$ ) across the diode the monitor current can be adjusted (and so the laser light output power) if one knows that the control circuit keeps the monitor voltage  $V_{mon}$  at a constant level of approximately 150 mV.

#### P-sub MONITOR

In this event pin 14 (ADJ) is connected via resistor  $R_{ADJp}$  to ground. The P-sub mode is selected and pin 14 (ADJ) acts as reference band gap voltage, providing together with  $R_{ADJp}$  an adjustable current  $I_{ADJ}$ . Now the control circuit keeps the monitor current at a level which is  $10I_{ADJ}$ .

The circuit is built up in three parts:

- The first part is the input stage which is able to switch between both modes (N-sub or P-sub).
- The second part is the integrator part which makes use of an external capacitor C<sub>L</sub>. This capacitor has two different functions:
  - During switch-on of the laser current, it provides a current slope of typically:

$$\frac{\Delta I_{o(L)}}{\Delta t} \cong \frac{10^{-6}}{C_L} \text{ (A/s)}$$

- After switch-on it ensures that the bandwidth equals

$$B_{P} \cong \frac{K \times G_{ext} \times 90 \times 10^{-9}}{C_{L} \times I_{mon}}$$
 (Hz)

in case of P-sub monitor or

$$B_{N} \cong \frac{R_{ADJn}}{C_{L}} K \times G_{ext} \times 870 \times 10^{-9}$$
 (Hz)

in case of N-sub monitor, where  $G_{ext}$  represents the AC gain of an extra loop amplifier, if applied, and  $K = \Delta I_{mon} / \Delta I_L$  which is determined by the laser/monitor unit.  $I_{mon}$  is the average current (pin 17) at typical light emission power of the laser diode.

• The third part is the power output stage, its input being the integrator output signal. This stage has a separate supply voltage (V<sub>DDL</sub>), thereby offering the possibility of reduced power consumption by supplying this pin with the minimum voltage necessary.

It also has a laser diode protection circuit which comes into action just before the driving output transistor will get saturated due to a large voltage dip on  $V_{DDL}$ . Saturation will result in a lower current of the laser diode, which normally is followed immediately by an increment of the voltage of the external capacitor  $C_L$ . This could cause damage to the laser diode at the end of the dip. The protection circuit prevents an increment of the capacitor voltage and thus offers full protection to the laser diode under these circumstances.

#### Photo diode signal filter and amplification section

This section has 6 identical current amplifiers. Amplifiers 1 to 4 are designed to amplify the focus photo diode signals. Each amplifier has two outputs: an LF output and an internal RF output. Amplifiers 5 and 6 are used for the radial photo diode currents and only have an LF output. All 6 output signals are low-pass filtered with a corner frequency at 69 kHz. The internal RF output signals are summed together and converted to a voltage afterwards by means of a selectable transresistance.

This transresistance R<sub>RF</sub> can be changed between 140 k $\Omega$  (3.3 V application) or 240 k $\Omega$  (5 V application) in combination with the P-sub monitor. In the event of the N-sub monitor selection, R<sub>RF</sub> can be changed between 70 k $\Omega$  (3.3 V application) and 120 k $\Omega$  (5 V application). The RF signal is available directly at pin 10 but there is also an unfiltered signal available at pin 9.

The used equalization filter has 2 different filter curves:

- One for single-speed mode
- One for double-speed mode.

### TDA1300T; TDA1300TT

 Table 1
 Gain and monitor modes

	PIN	MONITOR MODE R <sub>RF</sub> (kΩ)		INTENDED APPLICATION AREA
HG	ADJ			INTENDED APPLICATION AREA
0	R <sub>ADJp</sub> connected to ground	P-sub	140	3.3 V
0	1	N-sub	70	
1 <sup>(1)</sup>	R <sub>ADJp</sub> connected to ground	P-sub	240	5 V
1 <sup>(1)</sup>	1	N-sub	120	]

#### Note

1. Logic 1 or not connected.

#### Table 2 Speed and laser modes; note 1

			MOD	DE			
PIN	PIN DEFAULT VALUE <sup>(2)</sup>		SPEED		SER		
		SINGLE	DOUBLE	on	off		
LS	1	1	0	X <sup>(3)</sup>	X <sup>(3)</sup>		
LDON	1	X <sup>(3)</sup>	X <sup>(3)</sup>	1	0		

#### Notes

- 1. 1 = HIGH voltage ( $V_{DD}$ ); 0 = LOW voltage (GND); X = don't care.
- 2. If not connected.
- 3. X = don't care.

#### LIMITING VALUES

In accordance with the Absolute Maximum Rating System (IEC 134).

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
V <sub>DD</sub>	supply voltage		-	8	V
P <sub>max</sub>	maximum power dissipation		-	300	mW
T <sub>stg</sub>	storage temperature		-65	+150	°C
T <sub>amb</sub>	operating ambient temperature				
	TDA1300T		-40	+85	°C
	TDA1300TT		-40	+70	°C
V <sub>es</sub> <sup>(1)</sup>	electrostatic handling pin 16	note 2	-2	+2	kV
	electrostatic handling (all other pins)		-3	+3	kV

#### Notes

- 1. Classification A: human body model; C = 100 pF; R = 1500  $\Omega$ ; V<sub>es</sub> = ±2000 V. Charge device model: C = 200 pF; L = 2.5  $\mu$ H; R = 0  $\Omega$ ; V<sub>es</sub> = 250 V.
- 2. Equivalent to discharging a 100 pF capacitor through a 1.5 k $\Omega$  series resistor.

## TDA1300T; TDA1300TT

#### THERMAL CHARACTERISTICS

SYMBOL	PARAMETER	VALUE	UNIT
R <sub>th j-a</sub>	thermal resistance from junction to ambient in free air		
	TDA1300T	60	K/W
	TDA1300TT	128	K/W

#### QUALITY SPECIFICATION

In accordance with *"SNW-FQ-611 part E"*. The numbers of the quality specification can be found in the *"Quality Reference Handbook"*. The handbook can be ordered using the code 9397 750 00192.

#### CHARACTERISTICS

 $V_{DD}$  = 3.3 V;  $V_{DDL}$  = 2.5 V;  $T_{amb}$  = 25 °C;  $R_{ADJ}$  = 48 k $\Omega$ ; HG = logic 1; LS = logic 1; with an external low-pass filter ( $R_{ext}$  = 750  $\Omega$ ;  $C_{ext}$  = 47 pF) connected at the RFE output pin.

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
Supply	1			-	-	
I <sub>DD</sub>	supply current	laser off	-	7	-	mA
V <sub>DD</sub>	amplifier supply voltage		3	-	5.5	V
V <sub>DDL</sub>	laser control supply voltage		2.5	-	5.5	V
Р	power dissipation	laser off; V <sub>DD</sub> = 3 V	-	20	-	mW
Diode curre	nt amplifiers (n = 1 to 6; m = 1	to 6)		•	•	•
I <sub>i(d)</sub>	diode input current	note 1	_	_	10	μA
I <sub>n(i)(eq)</sub>	equivalent noise input current		-	1	-	pA/√Hz
V <sub>i(d)</sub>	diode input voltage	l <sub>i(d)</sub> = 1.67 μA	_	0.9	-	V
V <sub>o(d)</sub>	diode output voltage		-0.2	-	V <sub>DD</sub> – 1	V
G <sub>d(n)</sub>	diode current gain	$I_{i(d)} = 1.67 \ \mu A;$ $V_{o(d(n))} = 0 \ V; \text{ note } 2$	1.43	1.55	1.67	
I <sub>O(d)</sub>	diode offset current	$I_{i(central)} = I_{i(satellite)} = 0;$ note 3	_	-	100	nA
Z <sub>o(d)</sub>	output impedance	$I_{i(d)} = 1.67 \ \mu\text{A};$ $V_{o(d(n))} = 0 \ V$	500	-	-	kΩ
В	3 dB bandwidth	l <sub>i(d)</sub> = 1.67 μA	50	68	_	kHz
G <sub>mm</sub>	mismatch in gain between amplifiers	$I_{i(d)} = 1.67 \ \mu A;$ $V_{o(d(n))} = V_{o(d(m))}$	-	-	3	%

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
Data amplif	fier; equalized single and doub	le speed				
V <sub>O(RF)</sub>	DC output voltage	$I_{i(central)} = 0$	-	0.3	-	V
R <sub>RF</sub>	transresistance	N-sub monitor mode (low gain); note 3	56	70	84	kΩ
		N-sub monitor mode (high gain); note 3	96	120	144	kΩ
		P-sub monitor mode (low gain); note 4	112	140	168	kΩ
		P-sub monitor mode (high gain); note 4	200	240	285	kΩ
V <sub>O(RF)(max)</sub>	maximum output voltage	note 5	-	-	V <sub>DD</sub> – 1.2	V
SR <sub>RF</sub>	RF slew rate	V <sub>SR</sub> = 1 V (peak-to-peak)	_	6	_	V/µs
Z <sub>o(RF)</sub>	RF output impedance	f <sub>i</sub> = 1 MHz	-	100	-	Ω
t <sub>d(eq)</sub>	equalization delay		_	320	-	ns
t <sub>d(f)</sub>	flatness delay ( $\Phi/\omega$ )	LS = 1; note 6	-	10	-	ns
		LS = 0; note 6	-	5	-	ns
G/G	data amplifier gain ratio	note 6	4.5	6	-	dB
B <sub>RF</sub>	unequalized output bandwidth	l <sub>i(d)</sub> = 1.67 μA	3	5	-	MHz
Control pin	s LDON, LS and HG (with 47 k	$\Omega$ internal pull-up resistor	)	·		
V <sub>IL</sub>	LOW level input voltage		-0.2	_	+0.5	V
VIH	HIGH level input voltage		V <sub>DD</sub> – 1	_	V <sub>DD</sub> + 0.2	V
IIL	LOW level input current		-	-	100	μA
Laser outp	ut		•	•		•
V <sub>o(L)</sub>	output voltage	I <sub>o(L)</sub> = 100 mA	-0.2	-	V <sub>DDL</sub> - 0.7	V
I <sub>o(L)</sub>	output current		_	_	-100	mA
$\Delta I_{o(L)} / \Delta t$	slew rate output current	$C_L = 1 \text{ nF}$ (see Fig.8)	-	3.4	-	mA/μs
Monitor did	de input		•	•		
V <sub>ref</sub>	virtual reference voltage	N-sub monitor mode	130	150	170	mV
IL	leakage current	N-sub monitor mode	-	1	-	nA
V <sub>i(mon)</sub>	monitor input voltage	P-sub monitor mode	-	V <sub>DD</sub> - 0.7	-	V
I <sub>i(mon)</sub>	monitor input current	P-sub monitor mode	-	-	2	mA
ΔΤ	reference temperature drift	N-sub monitor mode	-	40	-	ppm
RS <sub>ref</sub>	reference supply rejection	N-sub monitor mode	_	_	1	%

### TDA1300T; TDA1300TT

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT	
Reference source V <sub>ADJ</sub> and laser adjustment current I <sub>ADJ</sub>							
V <sub>ref</sub>	reference voltage	$R_{ADJ} = 48 \text{ k}\Omega$	1.15	1.24	1.31	mV	
$\Delta T$	reference temperature drift		-	40	-	ppm	
RS <sub>ref</sub>	reference supply rejection		-	-	1	%	
I <sub>ADJ</sub>	adjustment current	$R_{ADJ} = 5.6 \text{ k}\Omega$	-	-	200	μA	
Zi	input impedance	$R_{ADJ} = 4.8 \text{ k}\Omega$	-	1	_	kΩ	
М	multiplying factor (I <sub>mon</sub> /I <sub>ADJ</sub> )		_	10	_	_	

#### Notes to the characteristics

1. The maximum input current is defined as the current in which the gain  $G_{d(n)}$  reaches its minimum. Increasing the supply voltage to  $V_{DD} = 5$  V increases the maximum input current (see also Figs 4 and 5).

2. The gain increases if a larger supply voltage is used (see Fig.6).

3. Transresistance of 70 k $\Omega$  and 120 k $\Omega$  (typical) is only available in N-sub monitor mode (see Table 1).

- 4. Transresistance of 140 k $\Omega$  and 240 k $\Omega$  (typical) is only available in P-sub monitor mode (see Table 1).
- 5. Output voltage swing will be:  $V_{O(RF)(swing)} = V_{O(RF)(max)} V_{O(RF)(p-p)}$ .
- 6. For single speed the data amplifier gain ratio is defined as gain difference between 1 MHz and 100 kHz, while the flatness delay is defined up to 1 MHz (see Fig.7). For double speed the data amplifier gain ratio is defined as gain difference between 2 MHz and 200 kHz, while the flatness delay is defined up to 2 MHz.

### TDA1300T; TDA1300TT

#### Transfer functions; see Fig.6

The equalized amplifier including  $C_{ext}$  and  $R_{ext}$  has the following transfer functions, where 'RFE' refers to equalized output only and 'RF' refers to equalized and not equalized outputs.

,

FOR SINGLE SPEED (SP = LOGIC 1)

$$\frac{V_{RFE}}{I_{i(central)}} = R_{RF} \times \frac{\left(1 - ks^2\right)/\omega_{os}^2}{1 + 1/Q \times s/\omega_{os} + s^2/\omega_{os}^2} \times \frac{1}{1 + s/\omega_1} \times \frac{1}{1 + sR_{ext} \times C_{ext}}$$
(1)

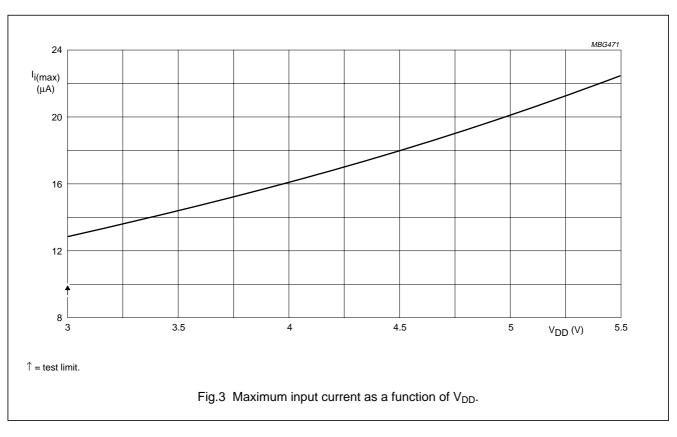
FOR DOUBLE SPEED (SP = LOGIC 0)

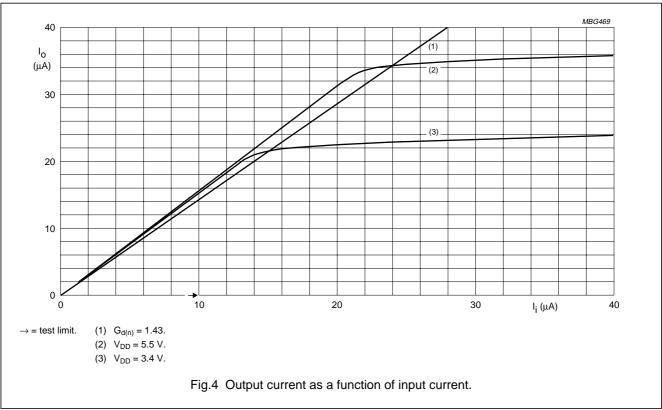
$$\frac{V_{RFE}}{I_{i(central)}} = R_{RF} \times \frac{\left(1 - ks^2\right)/\omega_{os}^2}{1 + 1/Q \times s/\omega_{od} + s^2/\omega_{od}^2} \times \frac{1}{1 + sR_{ext} \times C_{ext}}$$
(2)

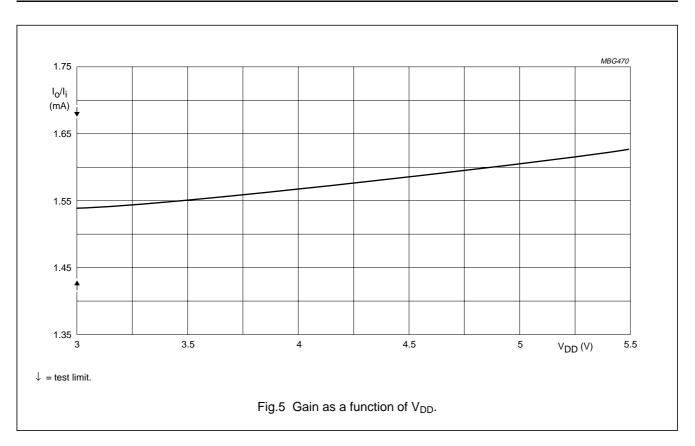
The denominator forms the denominator of a Bessel low-pass filter.

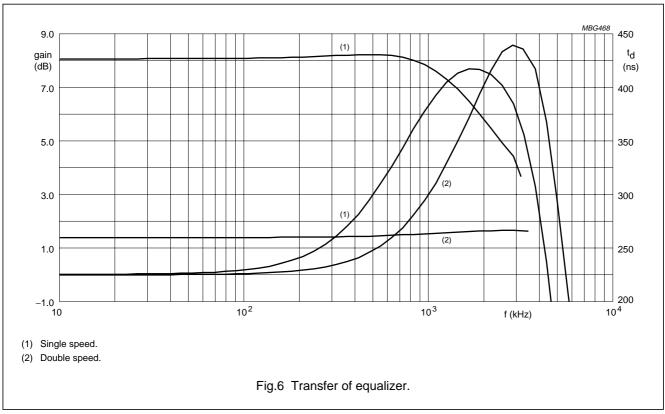
Symbols used in equations (1) and (2) are explained in Table 3.

SYMBOL	DESCRIPTION	TYP.	UNIT
k	internally defined	4	
$\omega_{os}/\omega_{1}$	internally defined	1.094	
Q	internally defined	0.691	
$\omega_{od} = 2 \times \omega_{os}$	internally defined	17.6 × 10 <sup>-6</sup>	rad/s
R <sub>RF</sub>	see Chapter "Characteristics"	-	
R <sub>ext</sub>	external resistor	750	Ω
C <sub>ext</sub>	external capacitor	47	pF



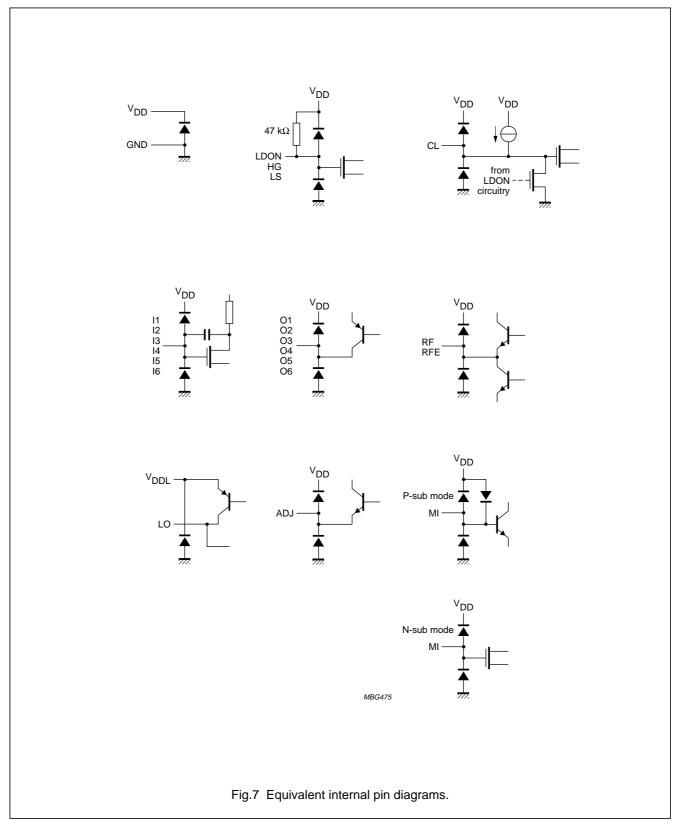






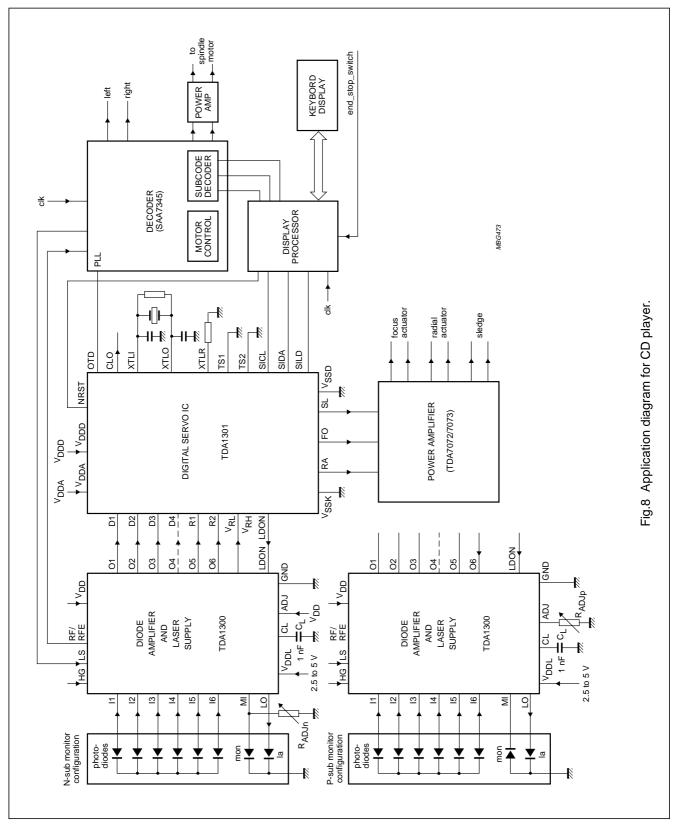
## TDA1300T; TDA1300TT

#### INTERNAL PIN CONFIGURATION



### TDA1300T; TDA1300TT

#### APPLICATION INFORMATION



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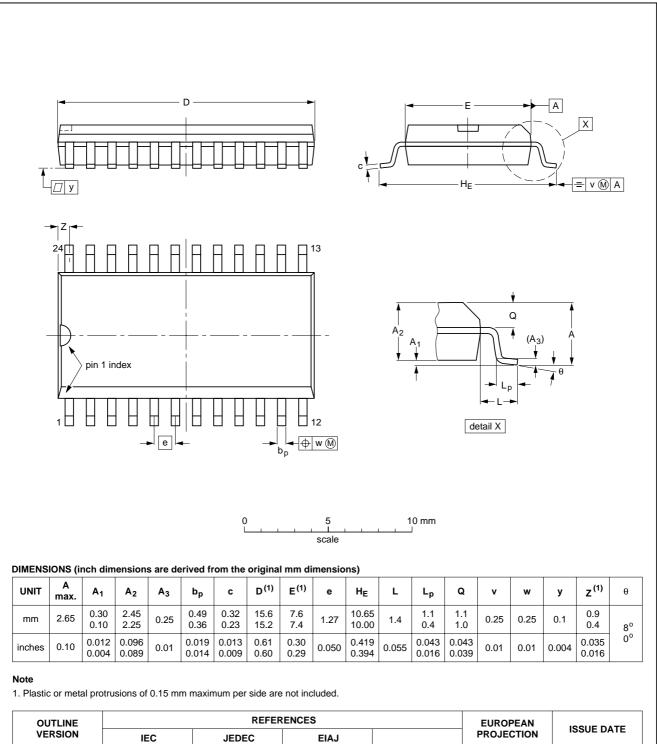
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TDA1300T; TDA1300TT

## Photodetector amplifiers and laser supplies

#### PACKAGE OUTLINES

#### SO24: plastic small outline package; 24 leads; body width 7.5 mm

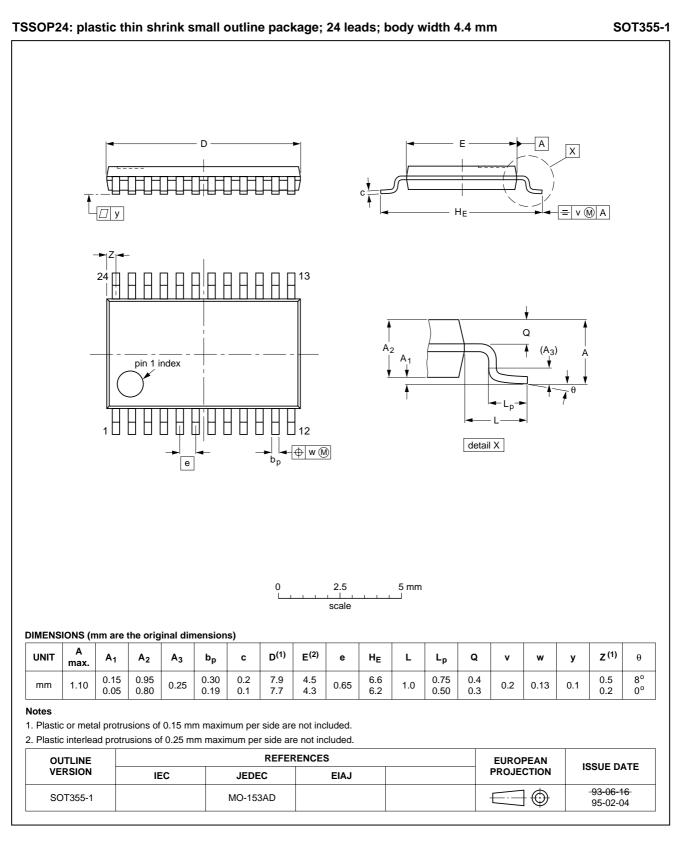


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TDA1300T; TDA1300TT

## Photodetector amplifiers and laser supplies

#### SOLDERING

#### Introduction

There is no soldering method that is ideal for all IC packages. Wave soldering is often preferred when through-hole and surface mounted components are mixed on one printed-circuit board. However, wave soldering is not always suitable for surface mounted ICs, or for printed-circuits with high population densities. In these situations reflow soldering is often used.

This text gives a very brief insight to a complex technology. A more in-depth account of soldering ICs can be found in our *"IC Package Databook"* (order code 9398 652 90011).

#### **Reflow soldering**

Reflow soldering techniques are suitable for all SO and TSSOP packages.

Reflow soldering requires solder paste (a suspension of fine solder particles, flux and binding agent) to be applied to the printed-circuit board by screen printing, stencilling or pressure-syringe dispensing before package placement.

Several techniques exist for reflowing; for example, thermal conduction by heated belt. Dwell times vary between 50 and 300 seconds depending on heating method. Typical reflow temperatures range from 215 to 250 °C.

Preheating is necessary to dry the paste and evaporate the binding agent. Preheating duration: 45 minutes at 45 °C.

#### Wave soldering

#### SO

Wave soldering techniques can be used for all SO packages if the following conditions are observed:

- A double-wave (a turbulent wave with high upward pressure followed by a smooth laminar wave) soldering technique should be used.
- The longitudinal axis of the package footprint must be parallel to the solder flow.
- The package footprint must incorporate solder thieves at the downstream end.

#### TSSOP

Wave soldering is **not** recommended for TSSOP packages. This is because of the likelihood of solder bridging due to closely-spaced leads and the possibility of incomplete solder penetration in multi-lead devices.

## If wave soldering cannot be avoided, the following conditions must be observed:

- A double-wave (a turbulent wave with high upward pressure followed by a smooth laminar wave) soldering technique should be used.
- The longitudinal axis of the package footprint must be parallel to the solder flow and must incorporate solder thieves at the downstream end.

Even with these conditions, do not consider wave soldering TSSOP packages with 48 leads or more, that is TSSOP48 (SOT362-1) and TSSOP56 (SOT364-1).

#### METHOD (SO AND TSSOP)

During placement and before soldering, the package must be fixed with a droplet of adhesive. The adhesive can be applied by screen printing, pin transfer or syringe dispensing. The package can be soldered after the adhesive is cured.

Maximum permissible solder temperature is 260 °C, and maximum duration of package immersion in solder is 10 seconds, if cooled to less than 150 °C within 6 seconds. Typical dwell time is 4 seconds at 250 °C.

A mildly-activated flux will eliminate the need for removal of corrosive residues in most applications.

#### **Repairing soldered joints**

Fix the component by first soldering two diagonallyopposite end leads. Use only a low voltage soldering iron (less than 24 V) applied to the flat part of the lead. Contact time must be limited to 10 seconds at up to 300 °C. When using a dedicated tool, all other leads can be soldered in one operation within 2 to 5 seconds between 270 and 320 °C.

## TDA1300T; TDA1300TT

#### DEFINITIONS

Objective specification       This data sheet contains target or goal specifications for product development.         Preliminary specification       This data sheet contains preliminary data; supplementary data may be published later.         Product specification       This data sheet contains final product specifications.         Limiting values       Limiting values given are in accordance with the Absolute Maximum Rating System (IEC 134). Stress above one or more of the limiting values may cause permanent damage to the device. These are stress ratings only and operation of the device at these or at any other conditions above those given in the Characteristics sections of the specification is not implied. Exposure to limiting values for extended periods may affect device reliability.	Data sheet status	
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Annilestian information	more of the limiting values of the device at these or at	may cause permanent damage to the device. These are stress ratings only and operation any other conditions above those given in the Characteristics sections of the specification
Application information	Application information	

Where application information is given, it is advisory and does not form part of the specification.

#### LIFE SUPPORT APPLICATIONS

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## TDA1300T; TDA1300TT

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Printed in The Netherlands

547027/50/03/pp20

Date of release: 1997 Jul 15

Document order number: 9397 750 01673

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